

Interplay of Touschek Scattering, Intrabeam Scattering, and RF Cavities in Ultralow-Emittance Storage Rings



## Introduction

- Ultralow-emittance storage rings  $\rightarrow \epsilon_x \ll 1 \text{ nm rad}$  (cf. later)
- Example: MAX IV 3 GeV storage ring

PRST-AB **17**, 050705 (2014)

20-fold 7BA lattice  $\rightarrow$  528 m,  $\varepsilon_0$  = 328 pm rad,  $U_0$  = 364 keV/turn



# Introduction (cont.)

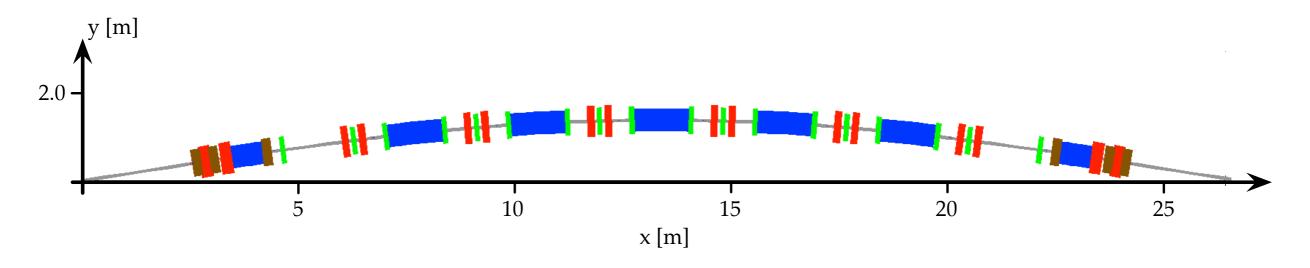
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PRST-AB **17**, 050705 (2014)

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PRST-AB **12**, 120701 (2009)

IPAC'**11**, THPC059, p.3029

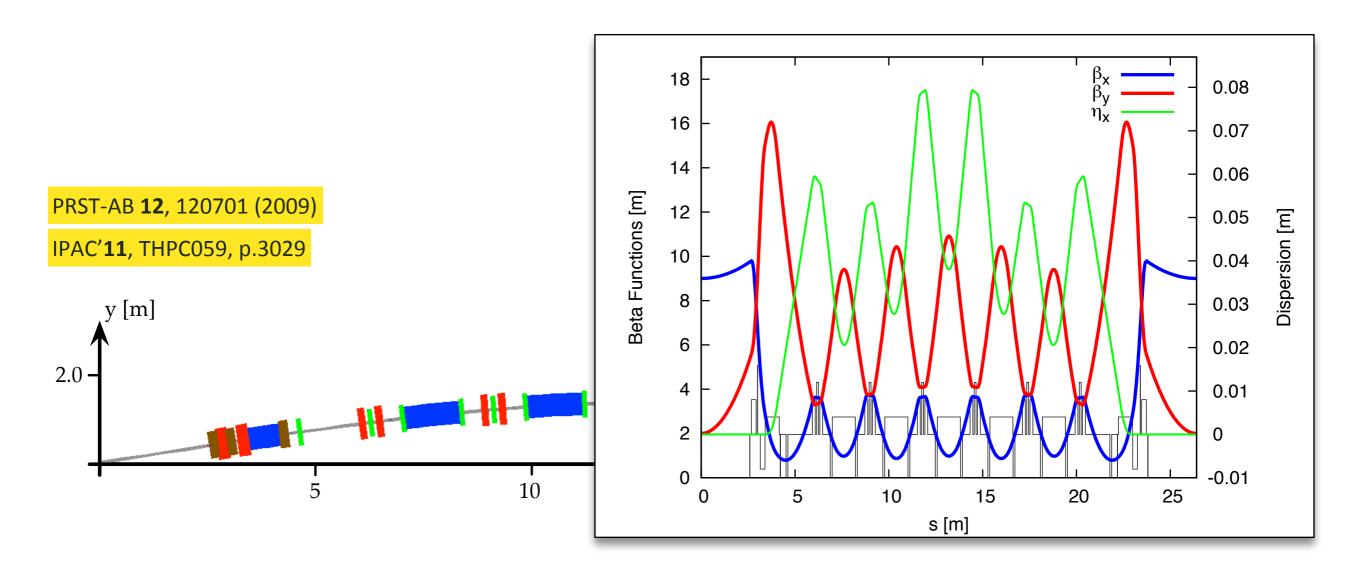


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PRST-AB **17**, 050705 (2014)

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# What makes these rings so different?

- 3rd generation SRs: emittance, radiated power,  $\sigma_{\delta} \approx \text{const}$
- Ultralow-emittance rings:
  - Use MBA lattices with many weak dipoles
  - DWs and/or IDs can have huge impact on radiated power

MAX IV 3 GeV SR:

Bare: 364 keV/turn

Loaded: ≈1 MeV/turn

$$U_0 \propto \gamma^4 I_2 \qquad I_2 = \int \frac{ds}{\rho^2}$$

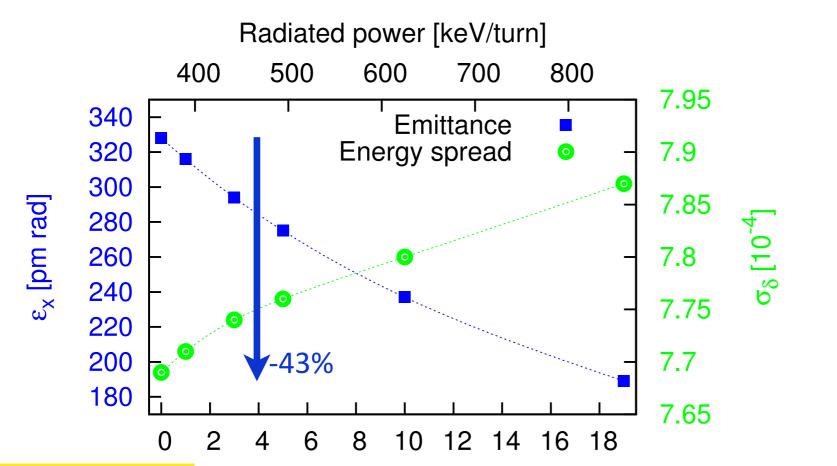
$$\varepsilon_0 \propto \gamma^2 \frac{I_5}{I_2 - I_4} \qquad I_5 = \int \frac{\mathcal{H}}{|\rho^3|} ds$$

$$I_4 = \int \frac{\eta}{\rho} \left( 2k + \frac{1}{\rho^2} \right) ds$$



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No. of installed IVUs

MAX IV 3 GeV SR:

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IVU: 3.7 m,  $\lambda_u$  = 18.5 mm,  $B_{eff}$  = 1.1 T

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- Ultralow-emittance rings:
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→ Emittance, energy spread, and radiated power are determined by installed IDs and gap settings MAX IV 3 GeV SR:

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# What makes these rings so different? (cont.)

- Furthermore, strong intrabeam scattering (IBS) as a consequence of ultralow emittance and high bunch charge at medium energy (compounded by low coupling)
   A. Piwinski, Proc. 9th HEAC, SLAC, 1974
   J. Le Duff, CERN Yellow Report 1989-01
- IBS leads to emittance blowup in all three planes (→ variation of bunch length & Touschek lifetime)
- Dependence of transverse emittance on stored current and bunch length (determined by varying radiated power & settings of main and harmonic cavities)

# An Intricate Interplay

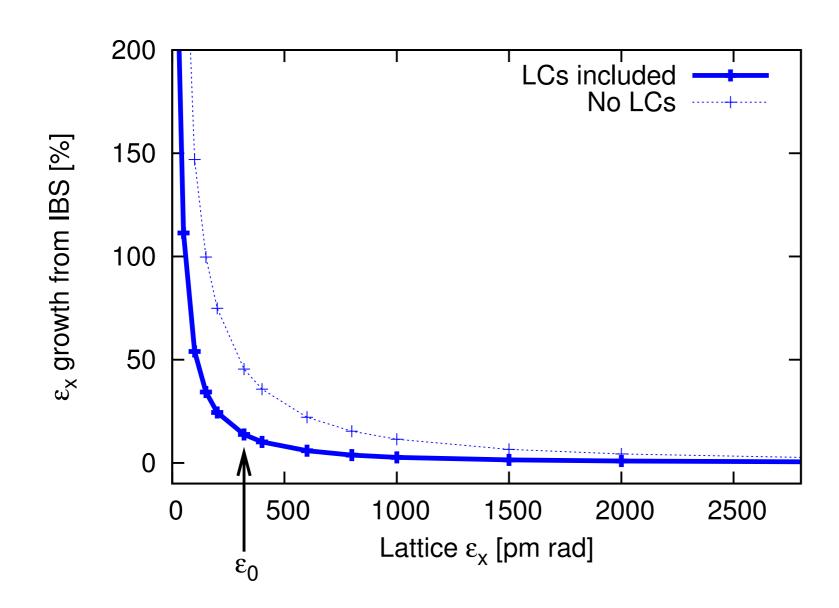
In ultralow-emittance rings (at medium energy), transverse dynamics ("emittance") and longitudinal dynamics (cavities → bunch length → Touschek lifetime) closely linked through IBS

→ As ID gaps change during user runs, all these parameters can vary (despite top-up)

→ Self-consistent treatment required for proper modeling

# **Emittance & Intrabeam Scattering**

# **How Serious is IBS Emittance Blowup?**



$$I = 500 \text{ mA}$$

$$\delta_{RF} = 4.5\%$$

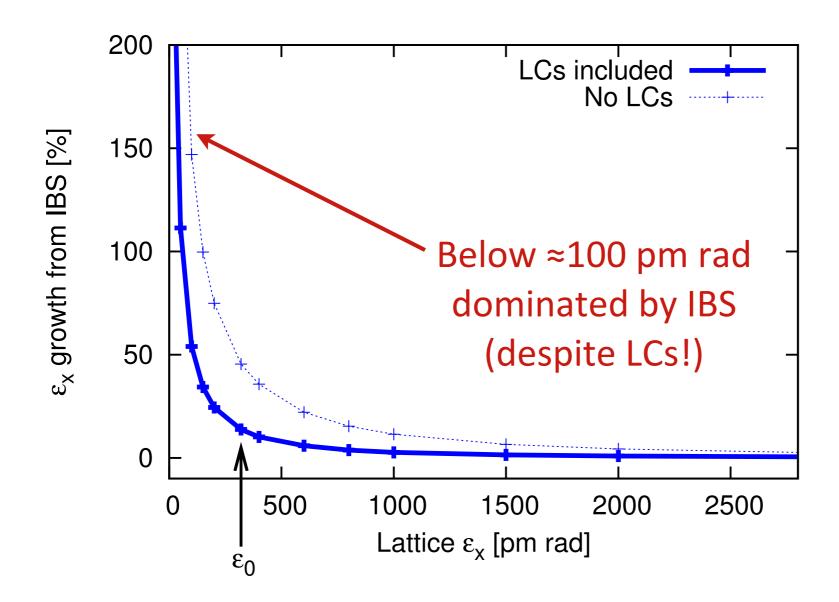
$$\sigma_{\delta} \approx \text{const}$$

$$\epsilon_{y} = 8 \text{ pm rad}$$

### For MAX IV 3 GeV SR (bare lattice):

- IBS blows up emittance by 45%
- LCs ( $\sigma_s \rightarrow \approx 5\sigma_s$ ) can reduce to 13%

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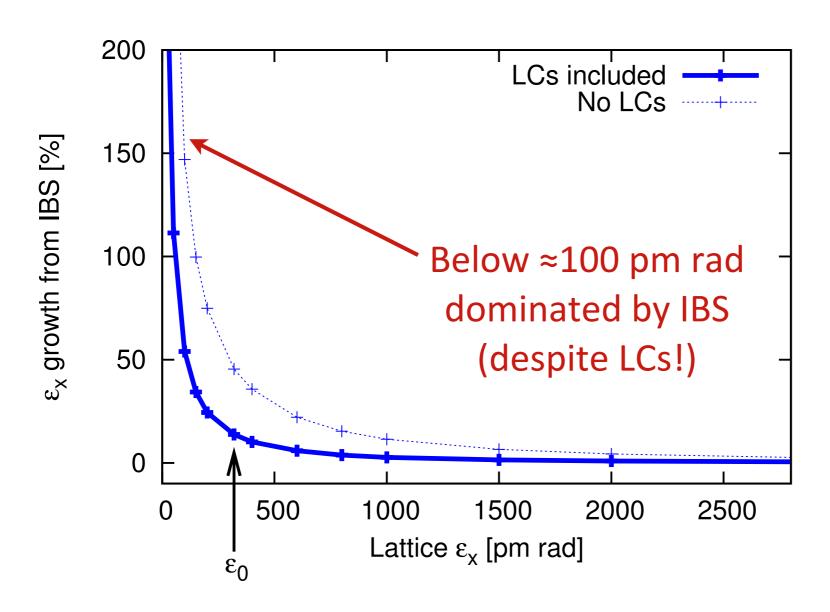


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PRST-AB **17**, 050705 (2014)

 Since emittance, energy spread, and bunch length depend so strongly on IDs and gap settings → in principle, need to calculate IBS for each storage ring configuration

# **Calculating Emittance with IBS**

Self-consistent approach with Tracy-3:

PRST-AB **17**, 050705 (2014)

- − rad. integrals → zero-current bare lattice parameters  $\varepsilon_0$ ,  $\sigma_\delta$ ,  $U_0$
- in addition, specify:
  - number/type of IDs installed and specific gap settings  $\rightarrow \epsilon_0$ ,  $\sigma_\delta$ ,  $U_0$
  - RF cavities at certain voltage and setting of harmonic LCs  $\rightarrow \delta_{RF}$ ,  $\sigma_s$
  - choice of emittance coupling (from errors and/or set via skew quads)  $\rightarrow \epsilon_x$ ,  $\epsilon_y$
  - single-bunch charge (MAX IV: 500 mA → 5 nC per bunch)
- calculate IBS growth rates and updated emittances in all three planes (following Bjorken-Mtingwa / Conte-Martini / MAD-X)

Part. Accel. 13, 115 (1983)

Part. Accel. 17, 1 (1985)

CERN-AB-2006-002

Iterate until equilibrium reached in all 3 planes

void IBS\_BM(Qb,eps[])
J. Bengtsson, V. Litvinenko (BNL)

→ New equilibrium emittances, bunch length, and energy spread

## A few examples:

		Zero-current	IBS	IBS & LCs
	$arepsilon_y$	$arepsilon_x$	$arepsilon_x$	$arepsilon_x$
Bare	8	320	466	364
	2	326	552	404
4 DWs / 10 IVUs	8	226	354	264
	2	232	436	302
Loaded	8	179	292	213
	2	185	365	247

PRST-AB **17**, 050705 (2014)

### **MAX IV 3 GeV SR**

I = 500 mA $U_{cav} = 1.8 \text{ MV}$ 

Two coupling settings:  $\varepsilon_y = 2 \text{ vs. } 8 \text{ pm rad}$ 

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PRST-AB **17**, 050705 (2014)

(+97%)

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PRST-AB **17**, 050705 (2014) (+34%)

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PAC'13, MOPHO05

 LCs stretch bunches by up to factor ≈5 → strong charge density dilution → reduce impact of IBS

IPAC'**11**, MOPC051

PRST-AB **4**, 030701 (2001)

PRST-AB 17, 064401 (2014)

• LCs employed in many SRs for stability & lifetime, PRST-AB 4, 0 but at MAX IV will become indispensable to preserve ultralow emittance during high-current top-up operation

# **Handling Emittance Variations**

- So considering emittance variations during user runs...
   ...do we need DWs to counteract effect of varying ID gaps?
  - gap motion usually uncorrelated between different beamlines
  - gaps not routinely ramped over large ranges
  - → Probably not necessary

# Handling Emittance Variations (cont.)

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   ...do we need DWs to counteract effect of varying ID gaps?
  - gap motion usually uncorrelated between different beamlines
  - gaps not routinely ramped over large ranges
  - → Probably not necessary
- However, could contemplate starting up with DWs in unoccupied straights to achieve lowest emittance; remove when user ID installed
  - Expensive! Cost of DWs & running cost (power bill)
  - Also, need to take care not to blow up electron beam's energy spread as this can spoil spectral flux/brightness

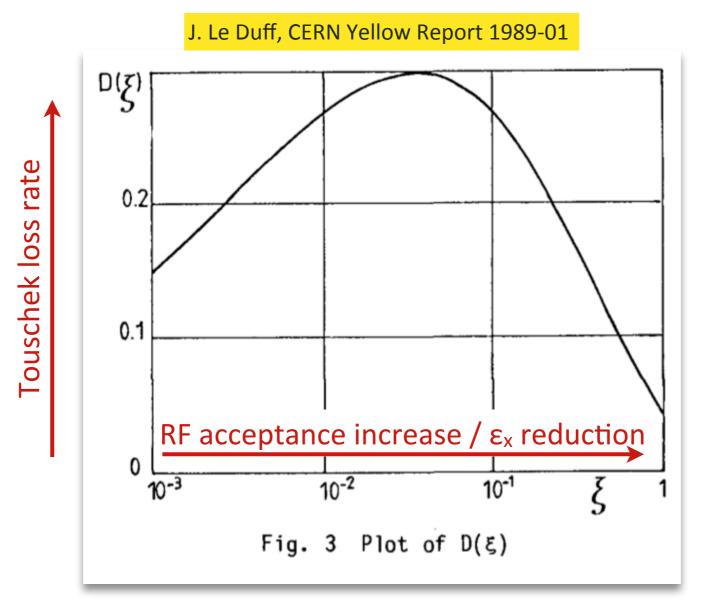


# Momentum Acceptance & Touschek Lifetime

 Despite ultralow emittance, can achieve good Touschek lifetime if MA is sufficiently large

PRL **10**, 407 (1963)

(low emittance → small transverse momenta → few events lead to actual Touschek loss, most lead to emittance blowup)



$$\xi = \left(\frac{\delta_{\mathrm{RF}}}{\gamma \sigma_{p_x}}\right)^2$$

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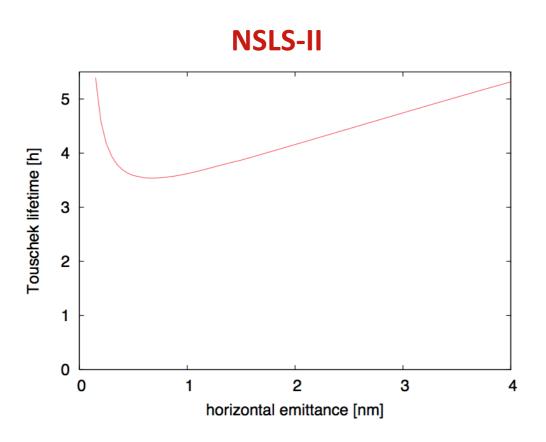


Figure 1: Touschek lifetime in NSLS-II as a function of horizontal emittance.

PAC'07, FRPMS113

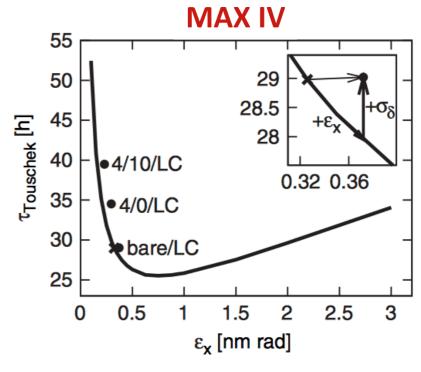


FIG. 15. The trend line shows Touschek lifetime for the bare lattice (IBS neglected) if it were possible to vary the lattice emittance while keeping the energy spread constant. Specific configurations (bare lattice, four PMDWs, and four PMDWs plus ten IVUs; all including LCs) are indicated by crosses and dots. Crosses indicate IBS neglected, dots indicate IBS included. The enlarged segment illustrates the effect of IBS for the bare lattice configuration: while the IBS emittance growth ( $+ \varepsilon_x$ ) leads to a decrease of Touschek lifetime, the IBS energy spread growth ( $+ \sigma_\delta$ ) leads to an increase of Touschek lifetime.

PRST-AB 12, 120701 (2009)

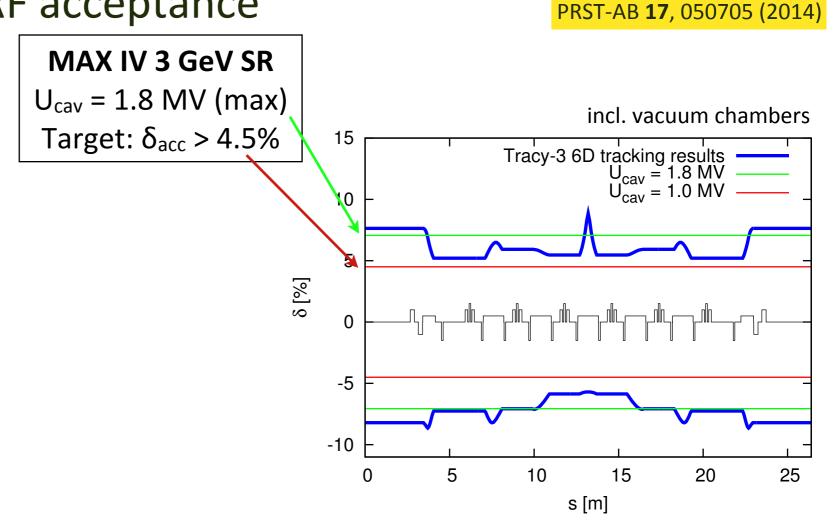


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 MAX IV 3 GeV SR lattice MA was therefore tailored to match and/or exceed large RF acceptance

PRST-AB 17, 050705

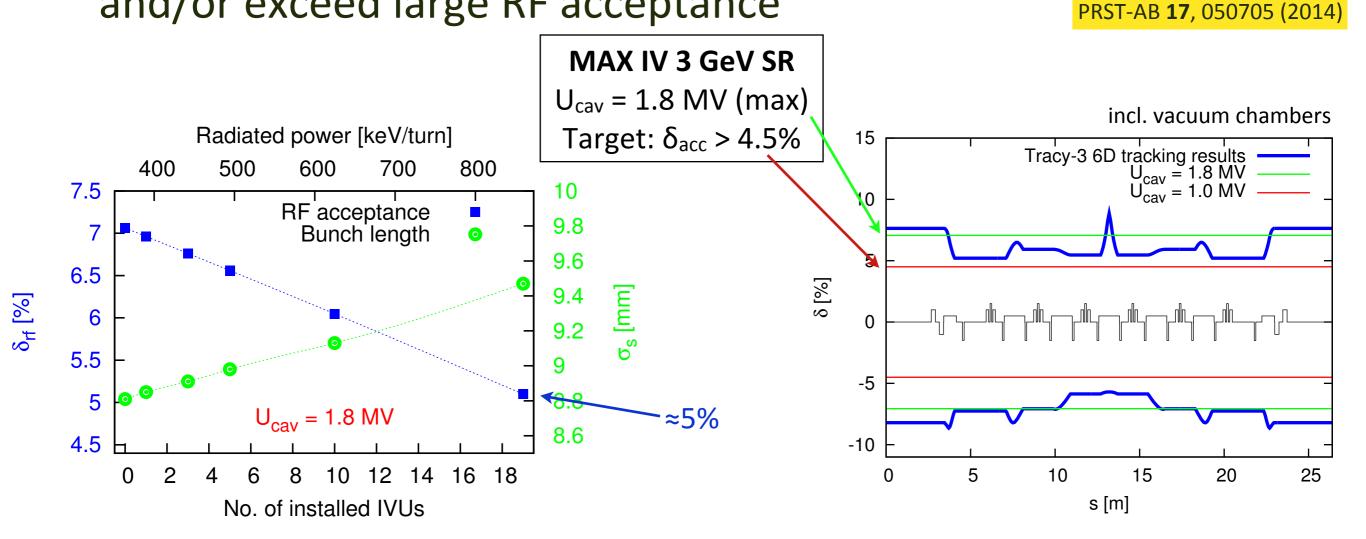


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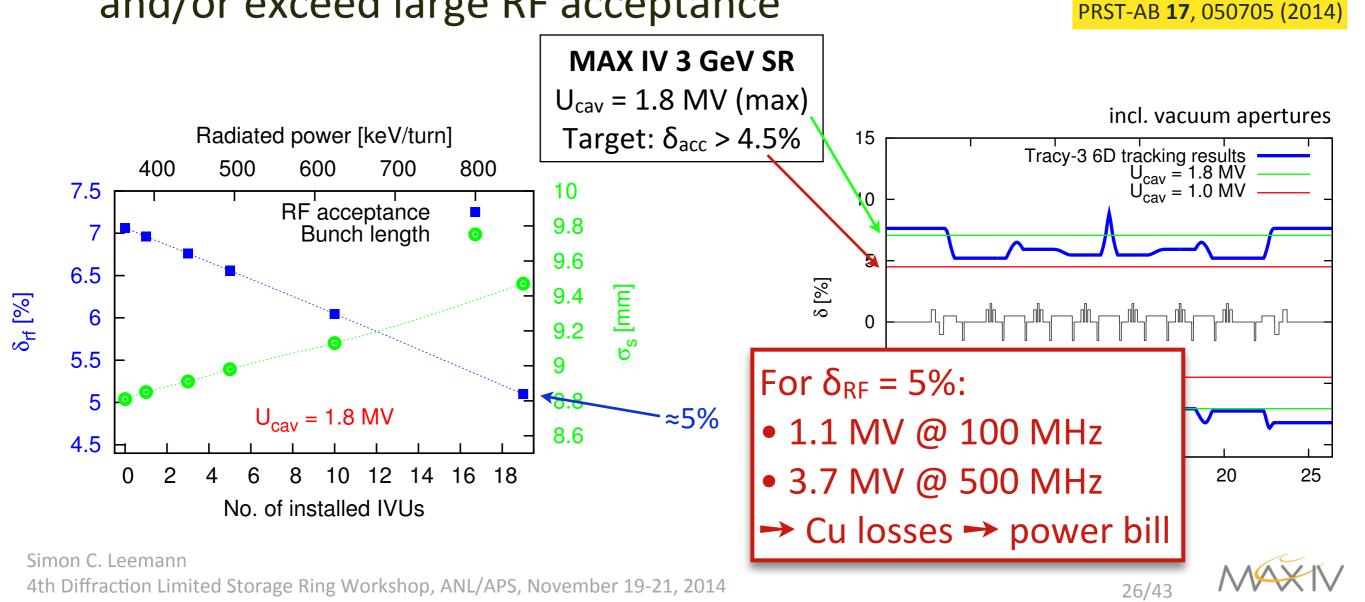


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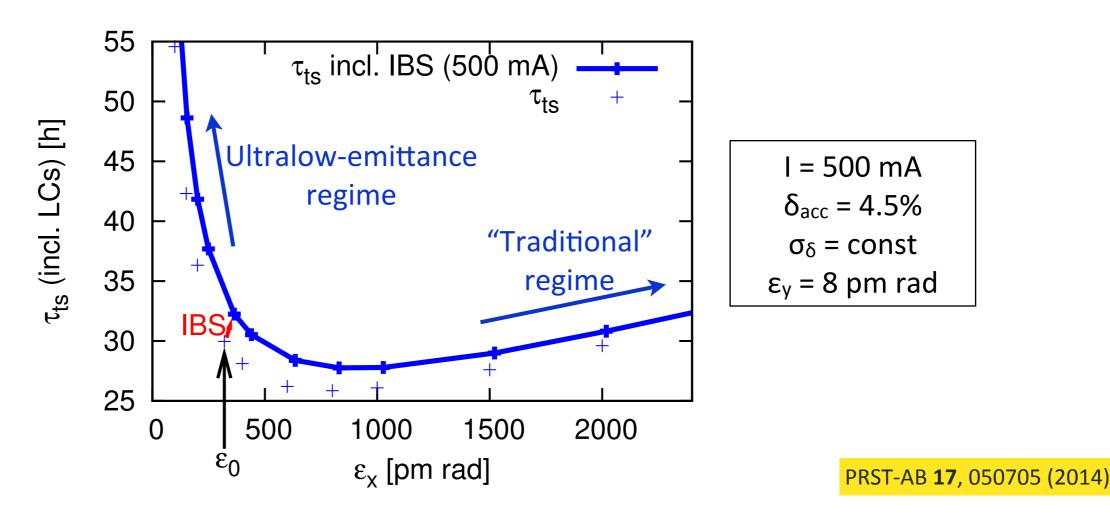
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PRST-AB 17, 050705



## **Touschek Lifetime Results**

Touschek lifetime reveals two distinctly different regimes



→ So should we install DWs and/or as many IDs as possible to get lowest emittance *and* best lifetime?

• 6D tracking results (self-consistent including IBS & vacuum apertures) for various configurations (max. RF voltage applied in each case)

PRST-AB <b>17</b> , 05070	$arepsilon$ (2014) $arepsilon_y$	$500\mathrm{mA}$	$500\mathrm{mA}$	Incl. errors &
	[pm rad]	no LCs	incl. LCs	$narrow gaps^1$
Bare	8	17.4	87.1	64.3
	2	9.6	45.9	40.7
4 DWs / 1	0 IVUs 8	20.5	114.3	66.2
	2	10.4	56.1	48.7
Loaded	8	11.7	65.0	37.7
	2	5.8	31.4	27.3

<sup>&</sup>lt;sup>1</sup>Narrow gaps have not been included in the bare lattice case.

### **MAX IV 3 GeV SR**

I = 500 mA $U_{cav} = 1.8 \text{ MV}$ 

Two coupling settings:  $\varepsilon_v = 2 \text{ vs. } 8 \text{ pm rad}$ 

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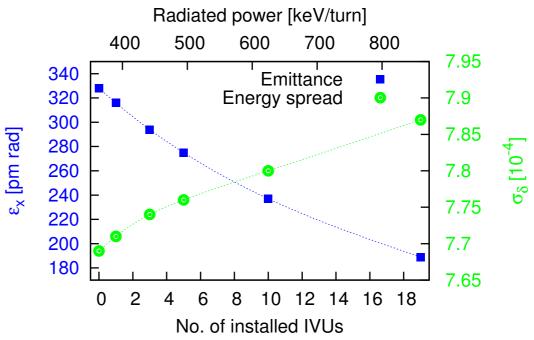
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PAC'13, MOPHO05

- Emittance reduces → lifetime increase
- RF acceptance reduces → lifetime reduction
- Overvoltage reduces → bunches stretched → minor lifetime increase (small effect)





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PRS	T-AB <b>17</b> , 050	705 (2014)	$arepsilon_y$	$500\mathrm{mA}$	$500\mathrm{mA}$	Incl. errors &
			[pm rad]	no LCs	incl. LCs	$narrow gaps^1$
	Bare	$\delta_{RF} = 7.1\%$	8	17.4	87.1	64.3
		ORF - 7.1/0	2	9.6	45.9	40.7
	4 DWs	/ 10 IVUs	8	20.5	114.3	66.2
		$\delta_{RF}$ = 6.1%	2	10.4	56.1	48.7
	Loaded	S F 40/	8	11.7	65.0	37.7
		$\delta_{RF} = 5.1\%$	2	5.8	31.4	27.3

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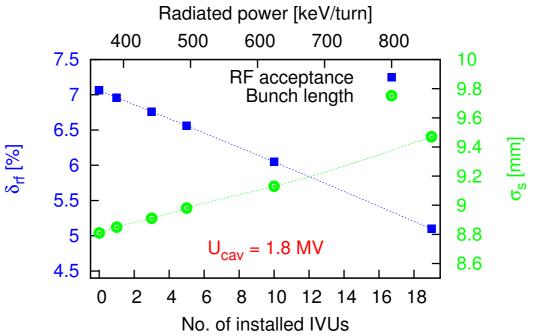
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•	Loaded	8	${11.7}$ +33	$\frac{1\%}{65.0}$	37.7
		2	5.8 (+22	<b>2%)</b> <u>31.4</u>	27.3

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(-44%)

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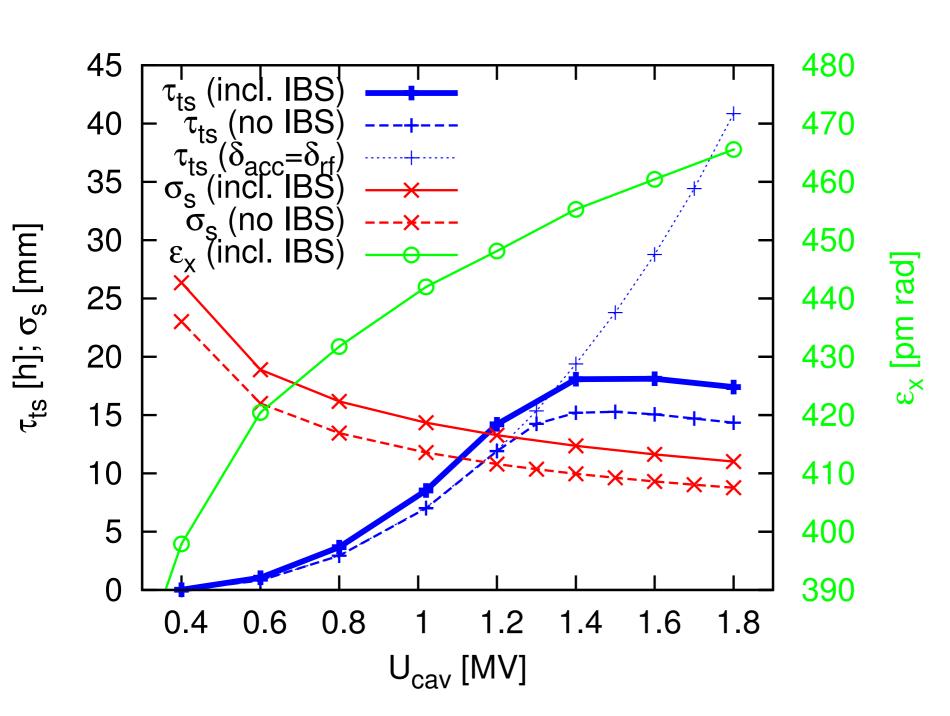
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PAC'13, MOPHO05

- Emittance reduces → lifetime increase
- RF acceptance reduces → lifetime reduction
- Overvoltage reduces → bunches stretched → minor lifetime increase (small effect)
  - → So, while adding many DWs and IDs will reduce emittance, this does not necessarily maximize lifetime (for a given RF system)

## RF Acceptance and Touschek lifetime

 $\bullet$  Emittance & Touschek lifetime incl. IBS as functions of  $\delta_{RF}$ 

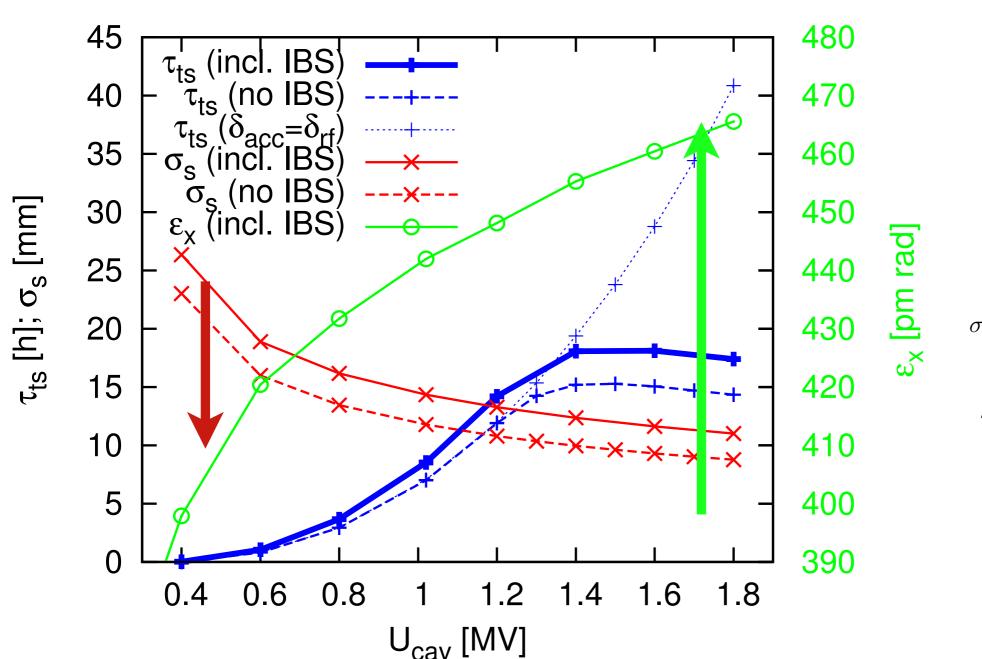


# MAX IV 3 GeV SR (bare lattice)

I = 500 mA  $\epsilon_y = 8 \text{ pm rad}$ LCs not included



ullet Emittance & Touschek lifetime incl. IBS as functions of  $\delta_{\mathsf{RF}}$ 



MAX IV 3 GeV SR (bare lattice)

I = 500 mA

 $\varepsilon_y$  = 8 pm rad

LCs not included

$$\sigma_s = \sigma_\delta \sqrt{\frac{\alpha h c^2}{f_{\rm RF} \cos \phi_s} q^{-1}} \quad q = \frac{e U_{\rm cav}}{U_0}$$

As cavity voltage increases



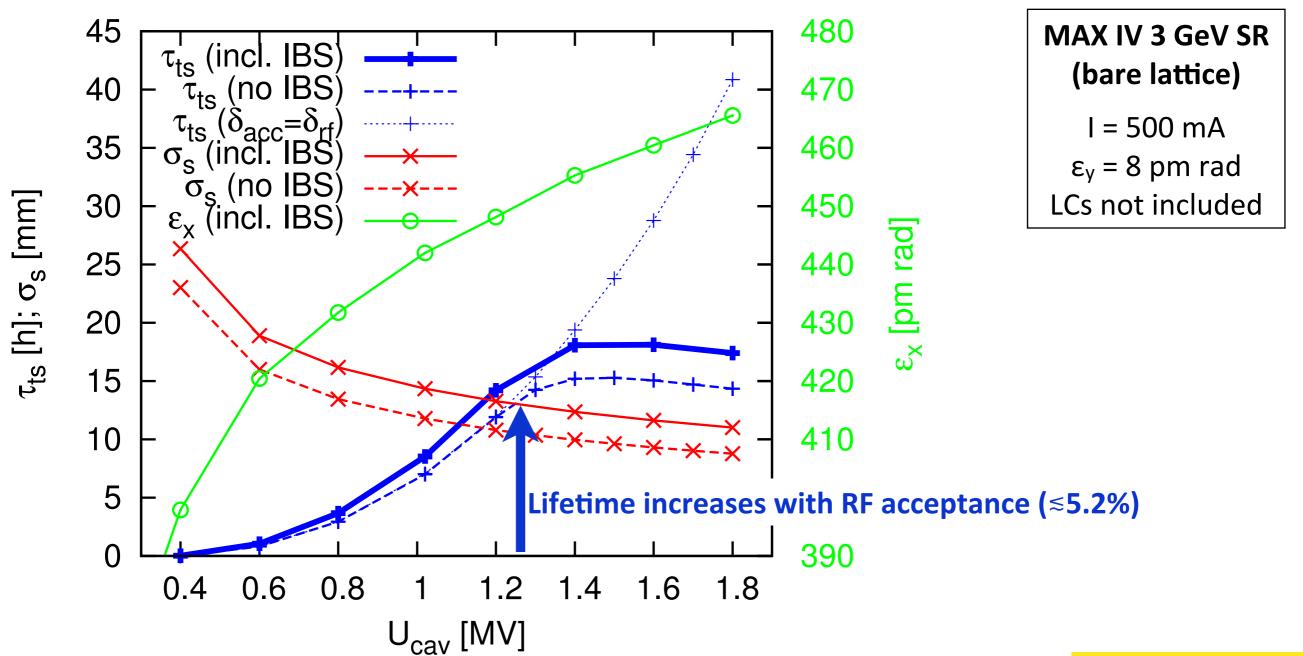
 $\sigma_s$  decreases



**Emittance increases (IBS)** 

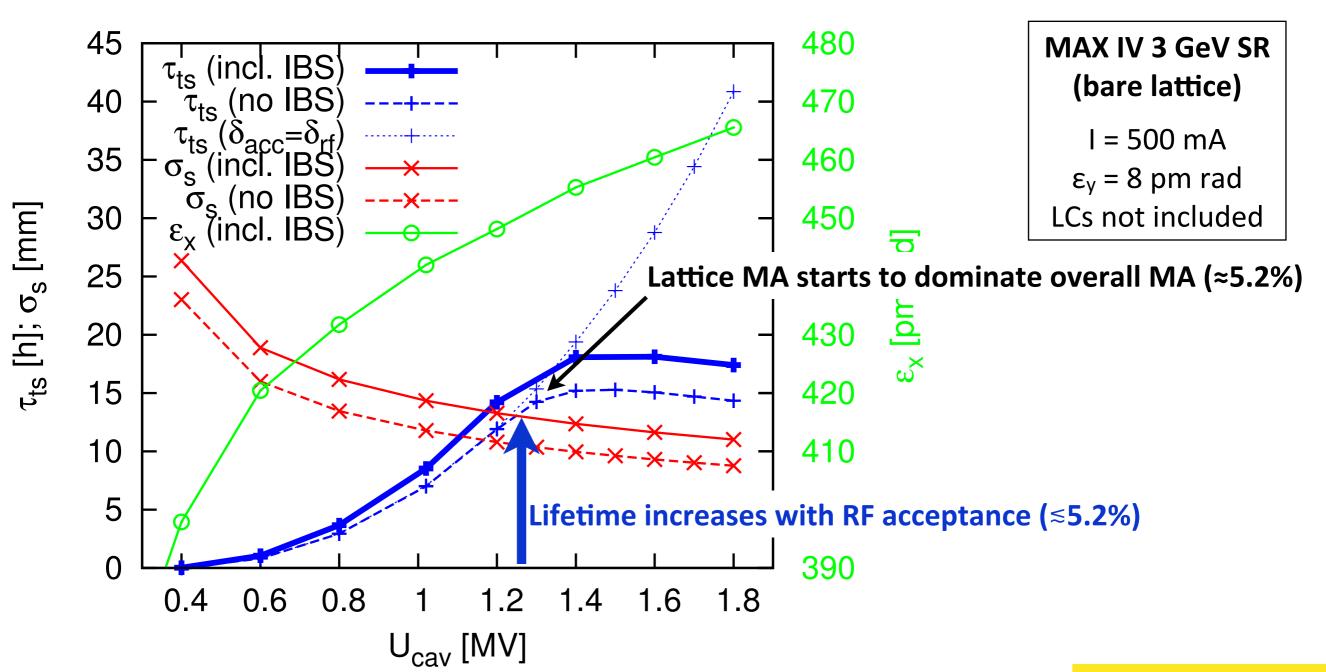


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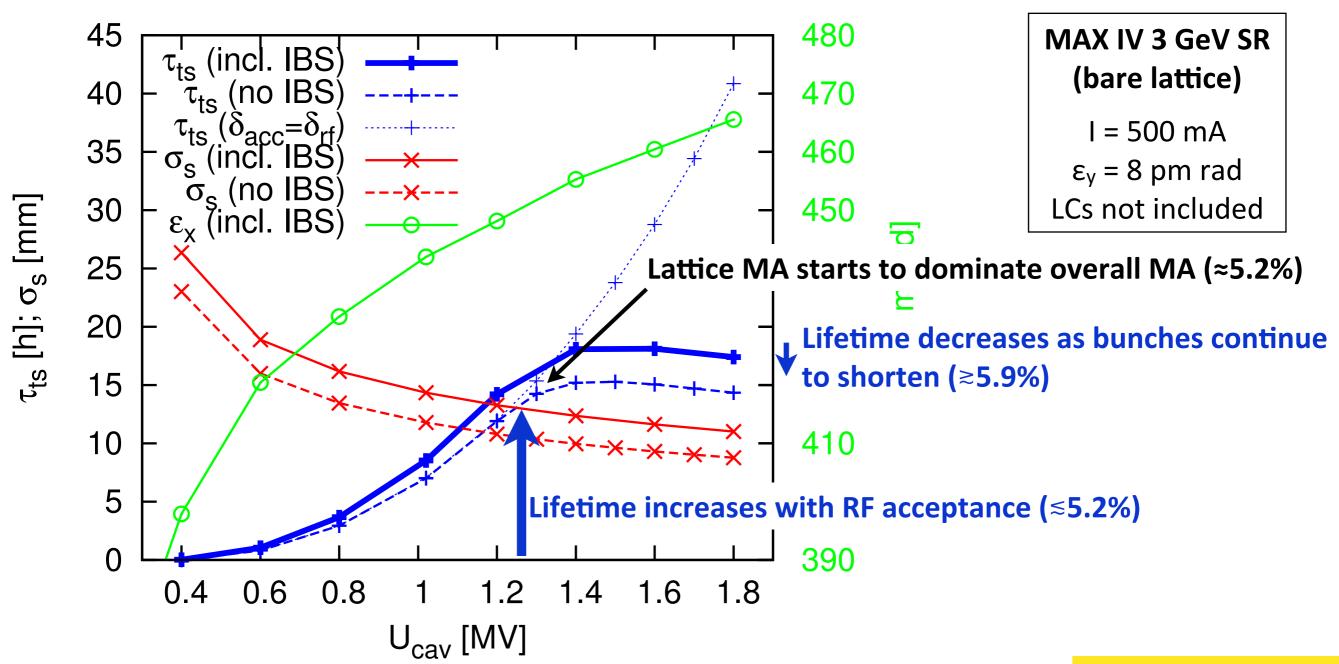


• Emittance & Touschek lifetime incl. IBS as functions of  $\delta_{RF}$ 





• Emittance & Touschek lifetime incl. IBS as functions of  $\delta_{\mathsf{RF}}$ 





## **Overall Lifetime**

 Touschek lifetime becomes so large, overall lifetime is no longer clearly Touschek-dominated

RST-A	AB <b>17</b> , 050705 (2014)	$arepsilon_y$	$500\mathrm{mA}$	$500\mathrm{mA}$	Incl. errors &
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### **MAX IV 3 GeV SR**

I = 500 mA $U_{cav} = 1.8 \text{ MV}$ 

Two coupling settings:  $\varepsilon_v = 2 \text{ vs. } 8 \text{ pm rad}$ 

PAC'13, MOPHO05

Worst-case scenario:  $\tau_{ts}$  = 27.3 ± 2.1 hrs (20 seeds)

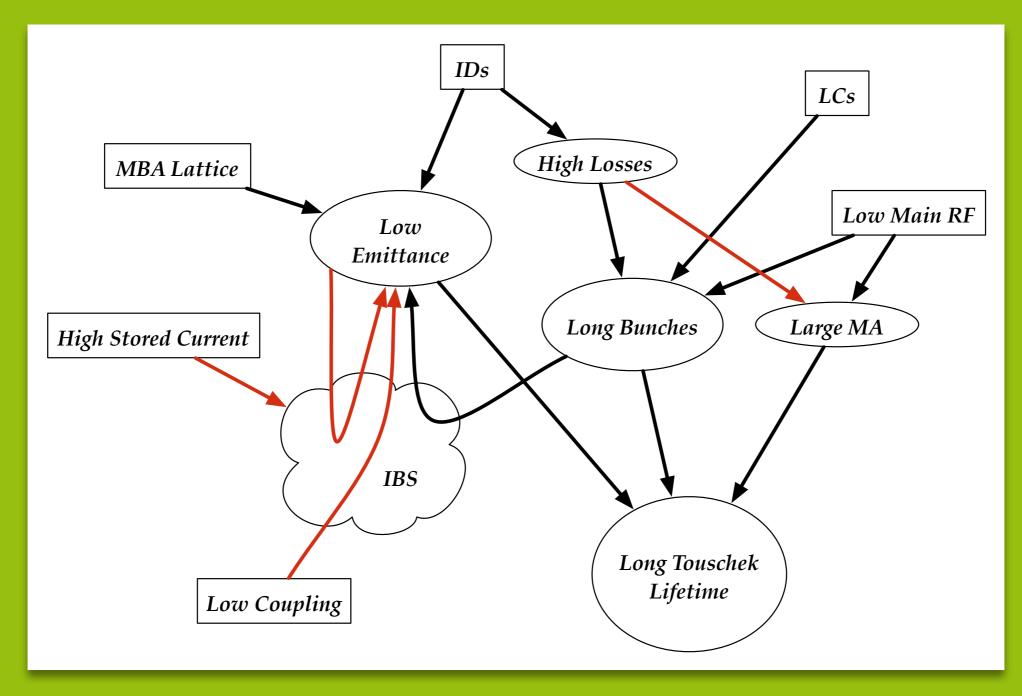
 $\tau_{ts} = 27 \text{ hrs}$ 

 $\tau_{el}$  = 25 hrs (2 pbar CO, incl. narrow gaps)

 $\tau_{bs} = 56 \text{ hrs}$  (weak dependence on MA, assumed 4.5%)

 $\rightarrow$   $\tau > 10 hrs (top-up shot required every few minutes @ 0.5% deadband)$ 

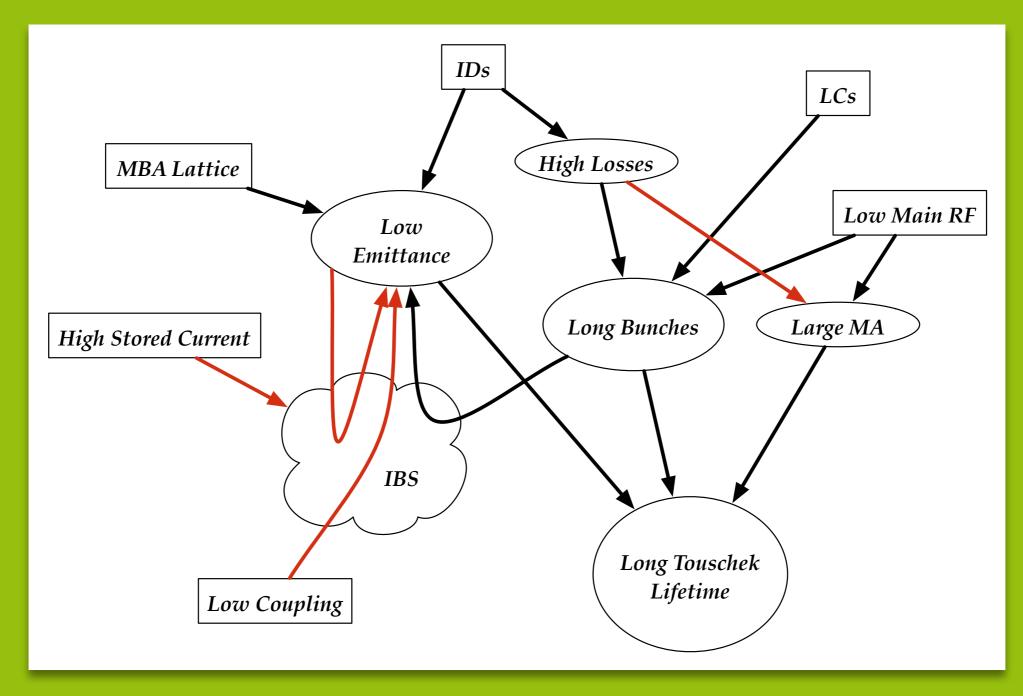
## Summary



- IBS (itself influenced by several factors) determines resulting emittance
- Emittance (as a result of IBS, but also ID & RF settings) determines resulting Touschek lifetime



# Summary (cont.)



- LCs allow storing high current & mitigate ε blowup from IBS
- → If overall system designed well, can achieve excellent lifetime despite ultralow ε

# **A Few Final Thoughts**

- Operating DLSRs with round beams will reduce impact of IBS
- Further increase bunch length → even lower RF?
- If short bunches are required → reduce stored current?
- Reduce bunch charge? → resulting spectral brightness & coherence at sample not necessarily maximized by storing largest possible amount of charge

